

Notice of References Cited	Application/Control No. 10/690,434	Applicant(s)/Patent Under Reexamination WANG ET AL.	
	Examiner Alexander O Williams	Art Unit 2826	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2003/0148618 A1	08-2003	Parikh, Suketu A.	438/694
*	B	US-6,656,837	12-2003	Xu et al.	438/676
*	C	US-6,541,397	04-2003	Bencher, Christopher Dennis	438/780
*	D	US-2003/0190812 A1	10-2003	Padhi et al.	438/694
*	E	US-2003/0194850 A1	10-2003	Lewis et al.	438/584
*	F	US-2003/0194857 A1	10-2003	Hau-Riege et al.	438/637
*	G	US-6,605,549	08-2003	Leu et al.	438/758
*	H	US-2003/0207558 A1	11-2003	Bao et al.	438/622
*	I	US-2003/0207560 A1	11-2003	Dubin et al.	438/629
*	J	US-2003/0207561 A1	11-2003	Dubin et al.	438/630
*	K	US-2003/0143837 A1	07-2003	Gandikota et al.	438/629
*	L	US-2004/0063310 A1	04-2004	Ngo et al.	438/637
*	M	US-2004/0029400 A1	02-2004	Gaillard et al.	438/778

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.